

Titles of Most Frequently Occurring Classifications of Patents Returned  
From A Search of 10614997 on November 03, 2005

7 714/724 (1 OR, 6 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing

6 324/158.1 (4 OR, 2 XR)  
Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/158.1 MISCELLANEOUS

6 324/754 (4 OR, 2 XR)  
Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF  
ELECTRIC COMPONENTS  
324/537 .of individual circuit component or element  
324/754 ..With probe elements

6 324/765 (5 OR, 1 XR)  
Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF  
ELECTRIC COMPONENTS  
324/537 .of individual circuit component or element  
324/765 ..Test of semiconductor device

6 714/733 (0 OR, 6 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/733 ..Built-in testing circuit (BILBO)

5 209/573 (0 OR, 5 XR)  
Class 209 : CLASSIFYING, SEPARATING, AND ASSORTING SOLIDS  
209/509 SORTING SPECIAL ITEMS, AND CERTAIN METHODS AND  
APPARATUS (E.G., POCKET TYPE AND LIGHT RESPONSIVE  
SORTING, ETC.) FOR SORTING ANY ITEMS  
209/552 .Condition responsive means controls separating  
means  
209/571 ..Electrical test sensing property of item  
209/573 ...Electrical component tested

5 324/758 (2 OR, 3 XR)  
Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF  
ELECTRIC COMPONENTS  
324/537 .of individual circuit component or element  
324/754 ..With probe elements  
324/758 ...Probe alignment or positioning

5 324/763 (4 OR, 1 XR)  
Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF  
ELECTRIC COMPONENTS  
324/537 .of individual circuit component or element  
324/763 ..DUT including test circuit

3 324/73.1 (0 OR, 3 XR)



10614997\_CLSTITLES.txt

714/699	PULSE OR DATA ERROR HANDLING
714/718	.Memory testing
2 714/719	(1 OR, 1 XR)
Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
714/699	PULSE OR DATA ERROR HANDLING
714/718	.Memory testing
714/719	..Read-in with read-out and compare
2 714/8	(2 OR, 0 XR)
Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
714/100	DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING
714/1	.Reliability and availability
714/2	..Fault recovery
714/3	...By masking or reconfiguration
714/5	....Of memory or peripheral subsystem
714/8	.....Isolating failed storage location (e.g., sector remapping)
2 716/4	(0 OR, 2 XR)
Class 716 :	DATA PROCESSING: DESIGN AND ANALYSIS OF CIRCUIT OR SEMICONDUCTOR MASK
716/1	CIRCUIT DESIGN
716/4	.Testing or evaluating